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Ito et al.

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(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

(71) Applicant: **HAMAMATSU PHOTONICS K.K.**,
Hamamatsu-shi, Shizuoka (JP)

(72) Inventors: **Masashi Ito**, Hamamatsu (JP); **Katsumi Shibayama**, Hamamatsu (JP); **Kazuto Ofuji**, Hamamatsu (JP); **Hiroki Oyama**, Hamamatsu (JP); **Yoshihiro Maruyama**, Hamamatsu (JP)

(73) Assignee: **HAMAMATSU PHOTONICS K.K.**,
Hamamatsu-shi, Shizuoka (JP)

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(51) **LOC (10) Cl.** **24-02**

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USPC **D24/225**

(58) **Field of Classification Search**
USPC D24/216, 222–226, 231, 232, 169;
D10/80, 81; 422/99, 100, 102, 68.1,
422/69, 560–566; 435/288.1, 288.3, 289.1,
435/283.1; 436/165

See application file for complete search history.

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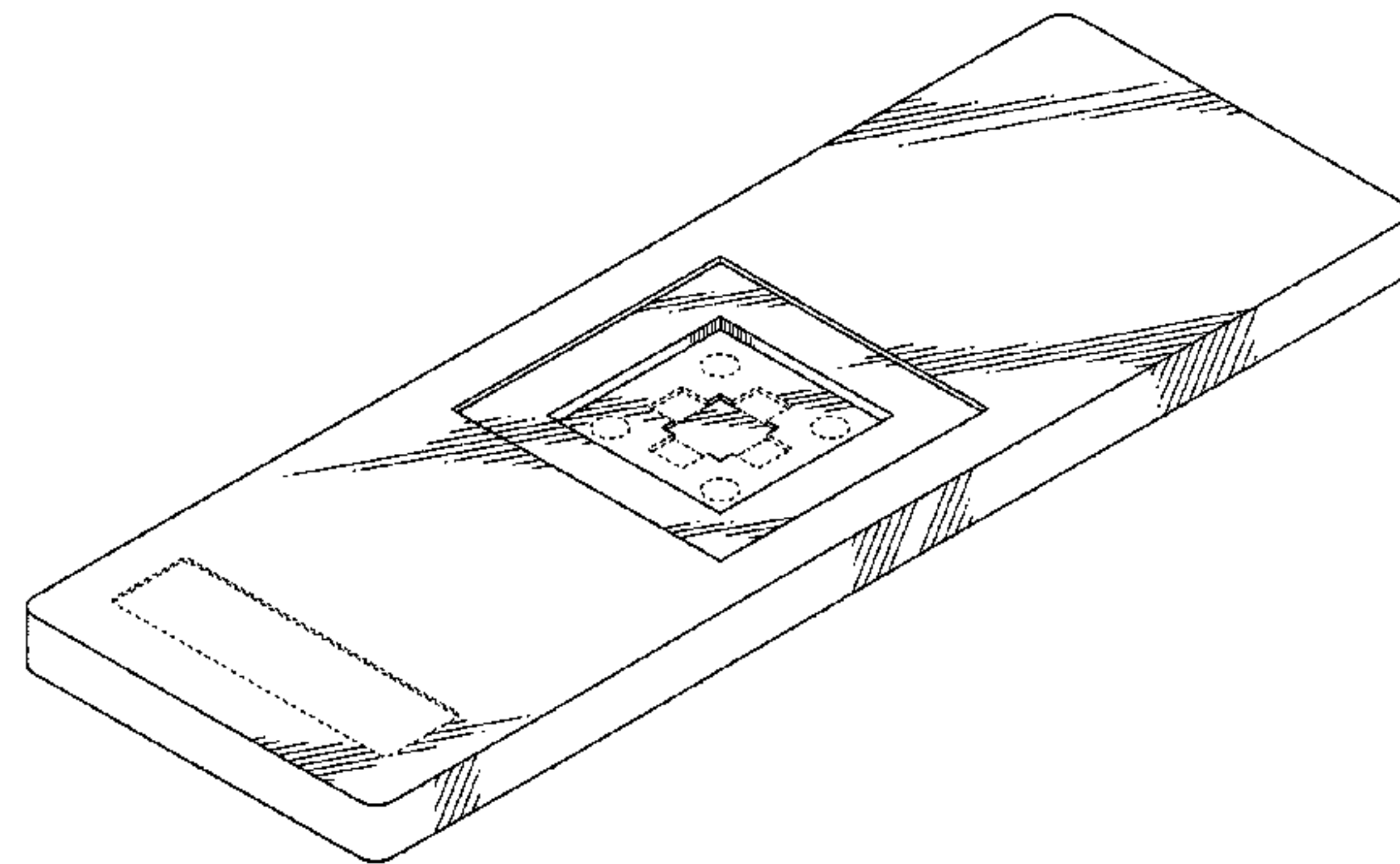
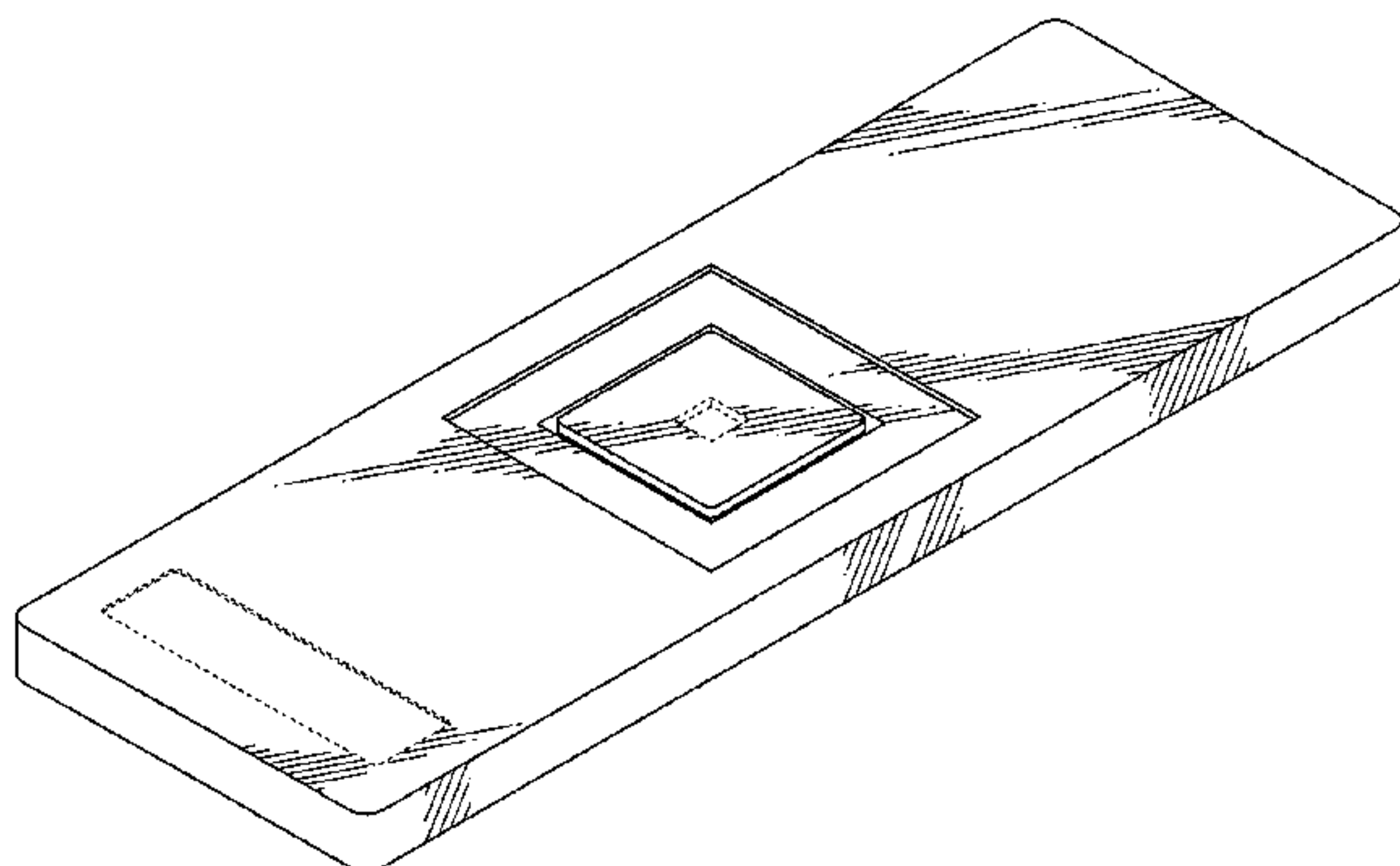
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Primary Examiner — T. Chase Nelson

Assistant Examiner — Mark Cavanna

(74) *Attorney, Agent, or Firm* — Drinker Biddle & Reath LLP



(57)

CLAIM

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

DESCRIPTION

FIG. 1 is a front view of a substrate for spectroscopic analysis according to our new design.

FIG. 2 is a rear view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 3 is a top plan view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 4 is a bottom view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 5 is a right side view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 6 is a left side view of the substrate for spectroscopic analysis of FIG. 1.

FIG. 7 is a perspective of the substrate for spectroscopic analysis of FIG. 1.

FIG. 8 is a top plan view without the cover part of the substrate for spectroscopic analysis of FIG. 1.

FIG. 9 is a perspective view without the cover part of the substrate for spectroscopic analysis of FIG. 1.

FIG. 10 is a sectional view taken along the line 10-10 of the substrate for spectroscopic analysis of FIG. 3.

FIG. 11 is a sectional view taken along the line 11-11 of the substrate for spectroscopic analysis of FIG. 1.

FIG. 12 is a sectional view taken along the line 12-12 of the substrate for spectroscopic analysis of FIG. 8.

FIG. 13 is an enlarged sectional view taken along the line 13-13 of the substrate for spectroscopic analysis of FIG. 10; and,

FIG. 14 is a reference sectional view taken along the line 10-10 of the substrate for spectroscopic analysis of FIG. 3 in use, wherein the element is inserted in the concave part for element and the glass plate is set above the cover part.

The features shown in dotted lines depict environmental subject matter only and form no part of the claimed design.

The broken lines having alternating long and short segments define bounds of the claimed design and form no part thereof.

The whole of the substrate for spectroscopic analysis of our design is transparent.

The broken lines show portions of the substrate for spectroscopic analysis that form no part of the claimed design.

1 Claim, 14 Drawing Sheets

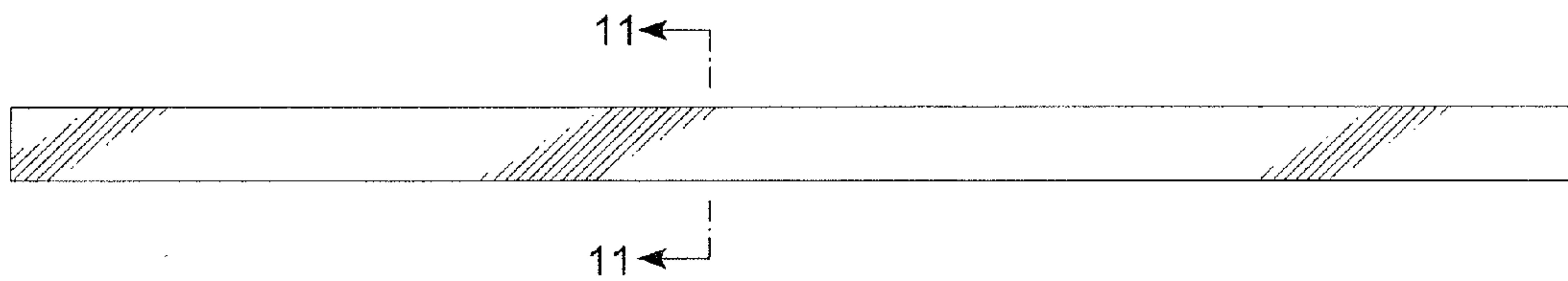


Fig. 1

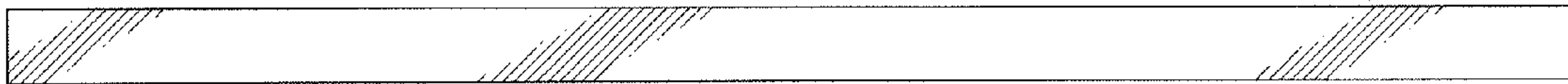


Fig.2

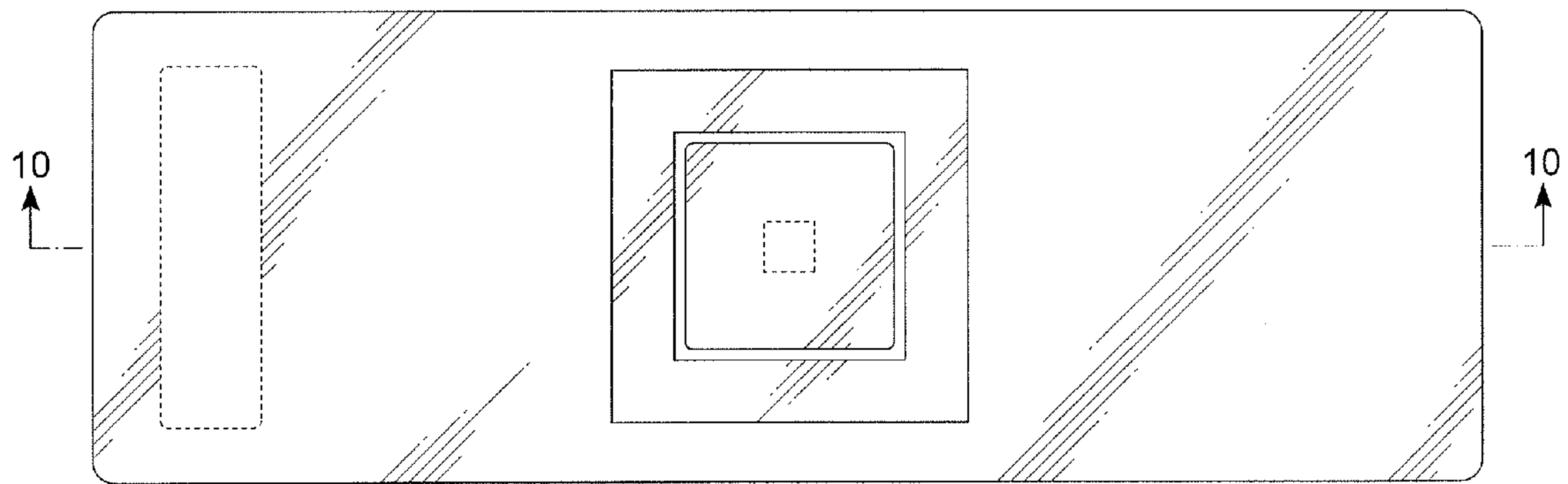


Fig.3

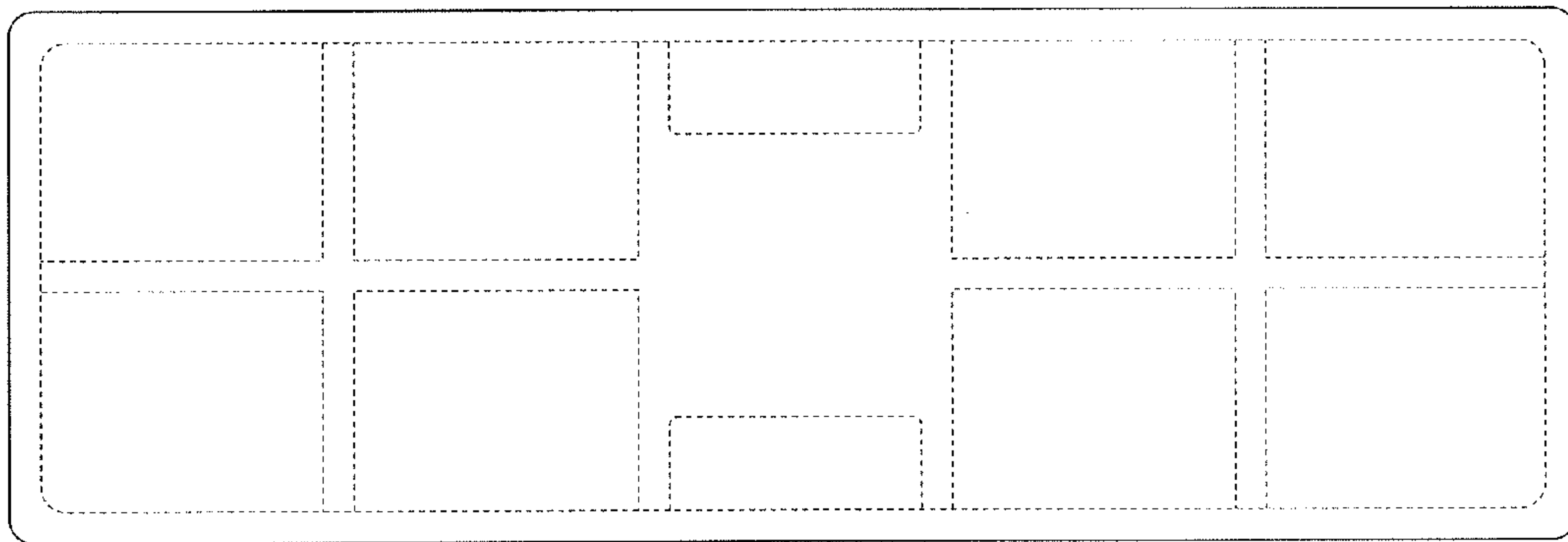


Fig.4



Fig.5

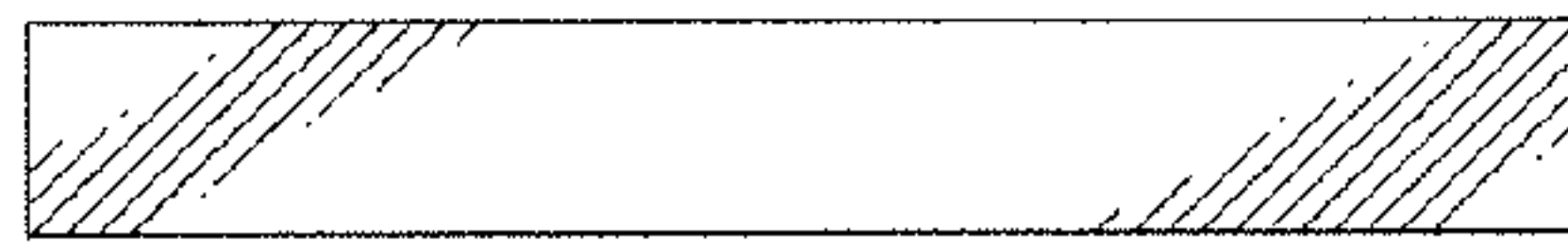


Fig.6

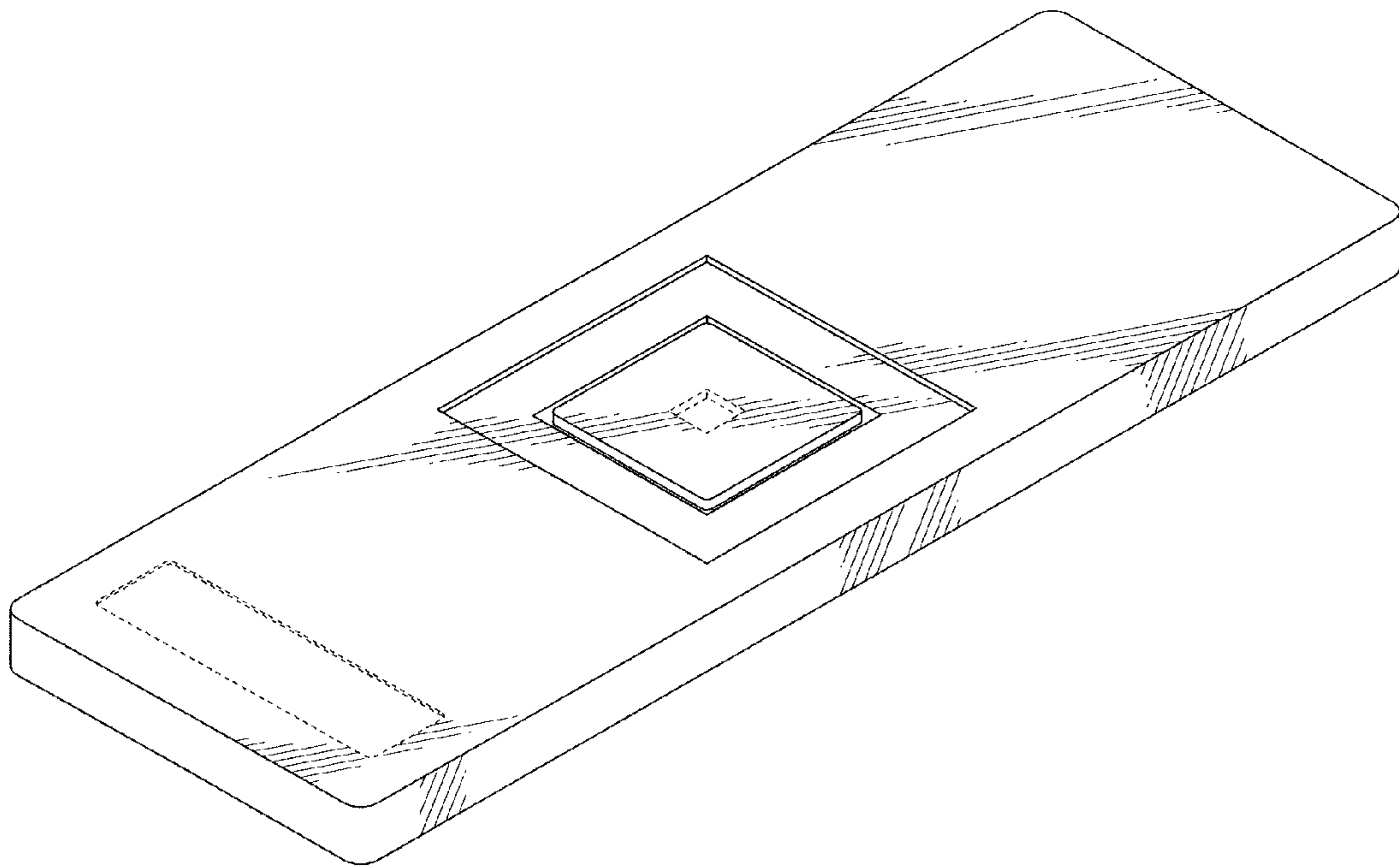


Fig.7

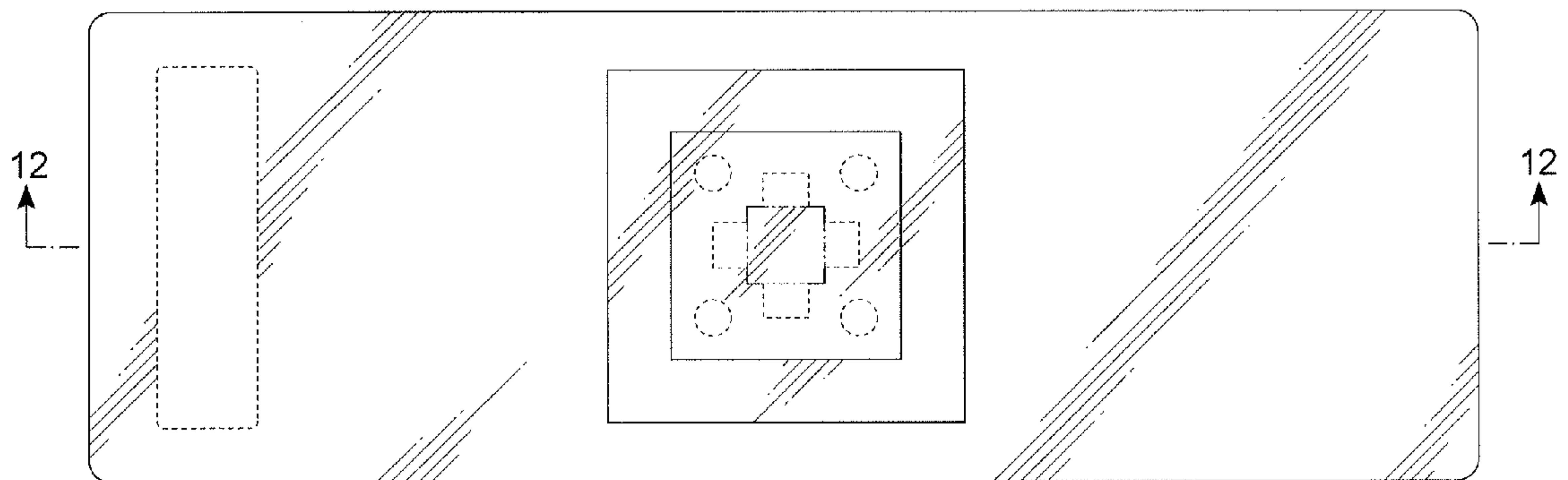


Fig.8

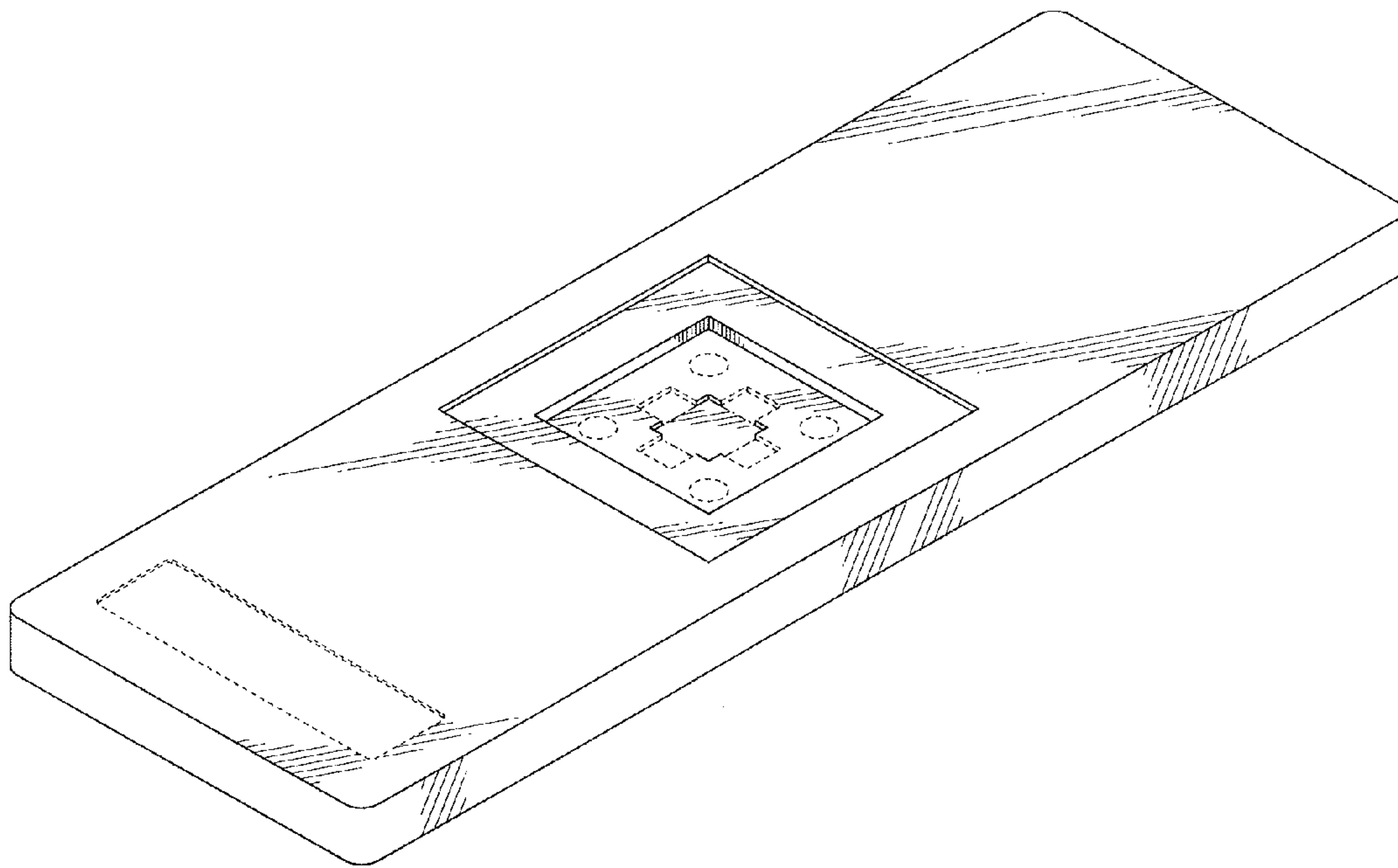


Fig.9

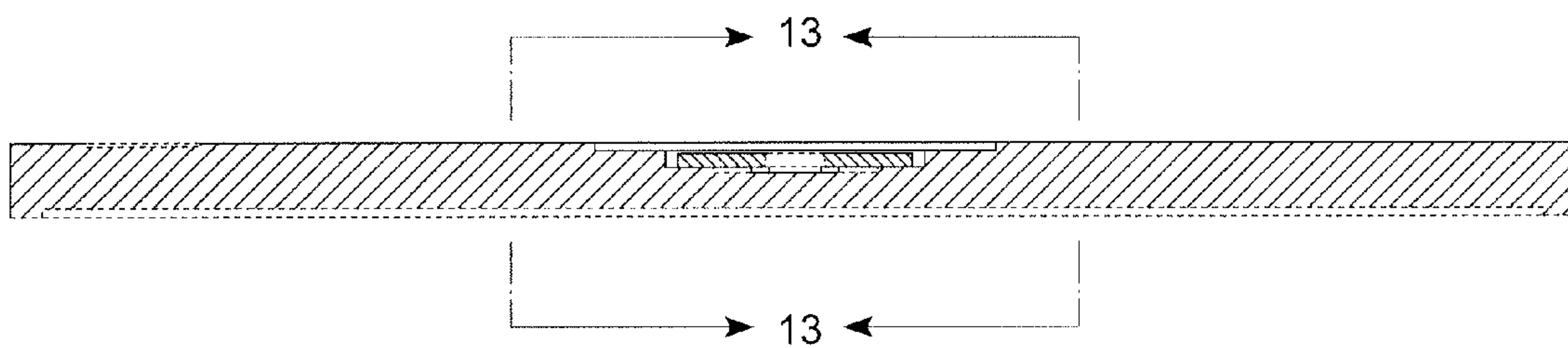


Fig.10

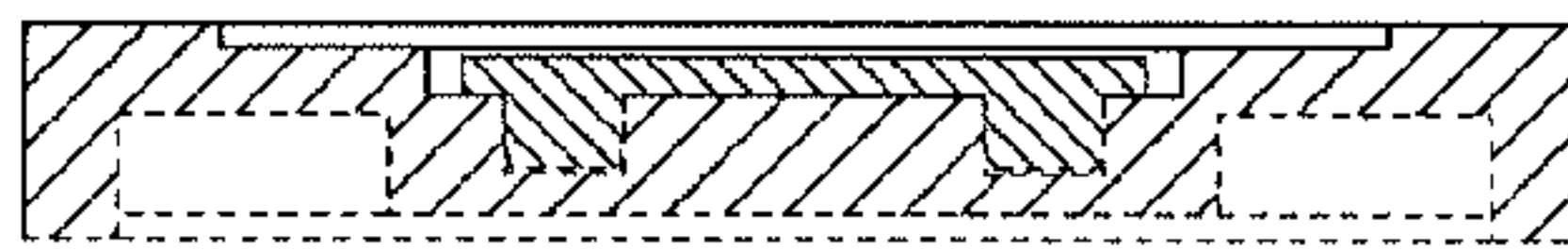


Fig.11

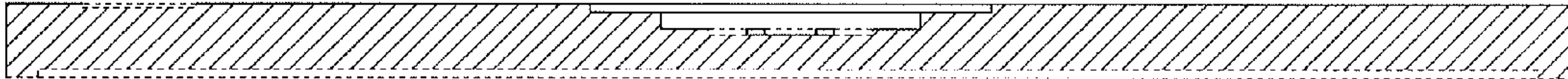


Fig.12

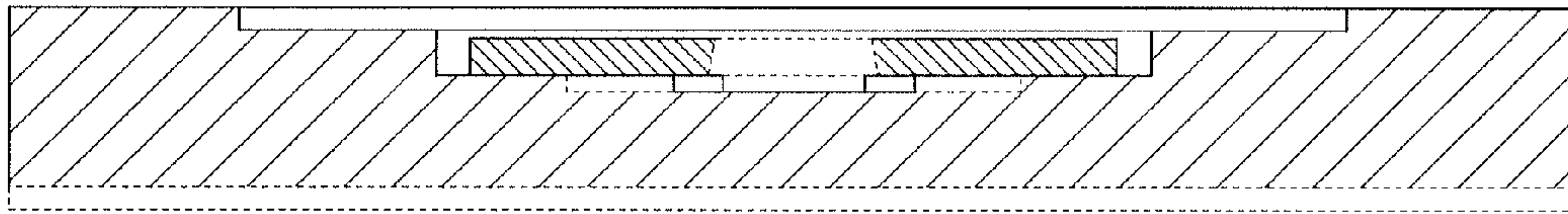


Fig.13

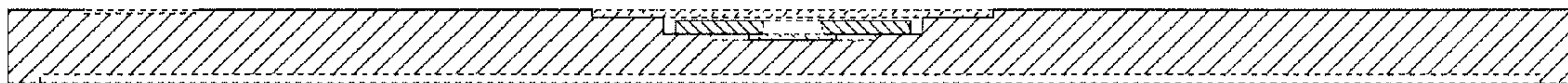


Fig.14